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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Johnston-Watt et al.

Attorney Docket No.: GILLP015X1

Application No.: 10/671,075

Examiner: Unassigned

Filed: September 25, 2003

Group: 2122

Title: VERIFIABLE PROCESSES IN A
HETEROGENEOUS DISTRIBUTED
COMPUTING ENVIRONMENT

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as first-class mail on June 24, 2004 in an envelope addressed to the Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450.

Signed: _____

Ann Lowe
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**INFORMATION DISCLOSURE STATEMENT
37 CFR §§1.56 AND 1.97(b)**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449, copies of which are attached, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement is not to be construed as a representation that a search has been made, that additional information material to the examination of this application does not exist, or that these references indeed constitute prior art.

This Information Disclosure Statement is: (i) filed within three (3) months of the filing date of the above-referenced application, (ii) believed to be filed before the mailing date of a first Office Action on the merits, or (iii) believed to be filed before the mailing of a first Office Action after the filing of a Request for Continued Examination under §1.114. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 500388 (Order No. GILLP015X1).

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Respectfully submitted,

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Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. GILLP015X1	Application No.: 10/671,075
	Applicant: Johnston-Watt et al.	
	Filing Date September 25, 2003	Group 2122

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub- class	Translation	
							Yes	No

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	1.	P.T. Wojciechowski; "The Nomadic PICT System. Release 1.0-alpha. Documentation and user's manual" 'Online!'; 19 Dec 2000 (2000-12-19), University of Cambridge; XP002282092; Retrieved from the Internet: URL:http://1srwww.epfl.ch/{pawel/npict-tutorial.ps.gz} retrieved on 2004-05-24! page 30- page 31
	2.	Kim Y G et al.: "Test cases generation from UML state diagrams"; IEE PROCEEDINGS: SOFTWARE, IEE, STEVENAGE, GB, vol. 146, no. 4, 24 Aug 1999 (1999-08-24), pages 187-192, XP006013720; ISSN: 1462-5970; page 189 – page 192.
	3.	B.C. Pierce, D.N. Turner: "PICT: A Programming language Based on the Pi-Calculus"; 19 Dec 2000 (2000-12-19),; XP002282093; pages 1,2,21.
	4.	Bemmerl T. et al.: "Programming Tools for Distributed Multiprocessor Computing Environments"; Future Generations Computer Systems; Elsevier Science Publishers, Amsterdam, NL; vol. 8, no. 1/3,; 1 July 1992 (1992-07-01), pages 221-234, XP000343134; ISSN: 0167-739X; page 229 – page 230.
	5.	Furukawa, Z. et al.; American Federation of Information Processing Societies: "Agent: An Advanced Test-Case Generation System for Functional Testing;; Proceedings of the National Computer Conference; Las Vegas, June 16-19, 1986, AFIPS Conference Proceedings, Reston, AFIPS Press, US,; vol. Vol. 55, 1 June 1986 (1986-06-01),; page 527 – page 531.

	6.	Rouger, A. et al.: "Test cases Generation From Formal Specifications"; Proceedings of the International Switching Symposium; Yokohama, Oct. 25 – 30, 1992, Tokyo, IEICE, JP; vol. vol. 2 SYMP. 14,; 25 Oct. 1992 (1992-10-25), pages 439-443,; XP000337756; page 439 – page 442.
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.